

<b>Notic of References Cited</b>	Application/Control No. 09/469,652		Applicant(s)/Patent Under Reexamination WIERER ET AL.	
	Examiner B. William Baumeister		Art Unit 2815	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,078,064	06-2000	Ming-Jiunn et al.	257/103
	B	US-5,760,423	06-1998	Kamakura et al.	257/99
	C	US-6,486,499	11-2002	Krames et al.	257/81
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Brown et al., "Ohmic contacts to Si-implanted and un-implanted n-type GaN," Mat. Res. Soc. Symp. Proc. Vol. 395, 1996 Materials Research Society, pp. 855-860.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.